

**Search Notes**

Application/Control No.

10/764,481

Examiner

MARK A. MAIS

Applicant(s)/Patent under  
Reexamination

HIYAMA ET AL.

Art Unit

2619

**SEARCHED**

Class	Subclass	Date	Examiner
370	310 328 329	6/16/2008	MAM
	331 338 351		
	352 353 389		
	392 401 469		
	474 475 476		
SAME AS	ABOVE	3/30/2008	MAM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search	6/16/2008	MAM
See Attached Electronic Search	6/16/2008	MAM
See Attached Electronic Search [updated]	3/30/2008	MAM